

# **ECE 340: Semiconductor Electronics**

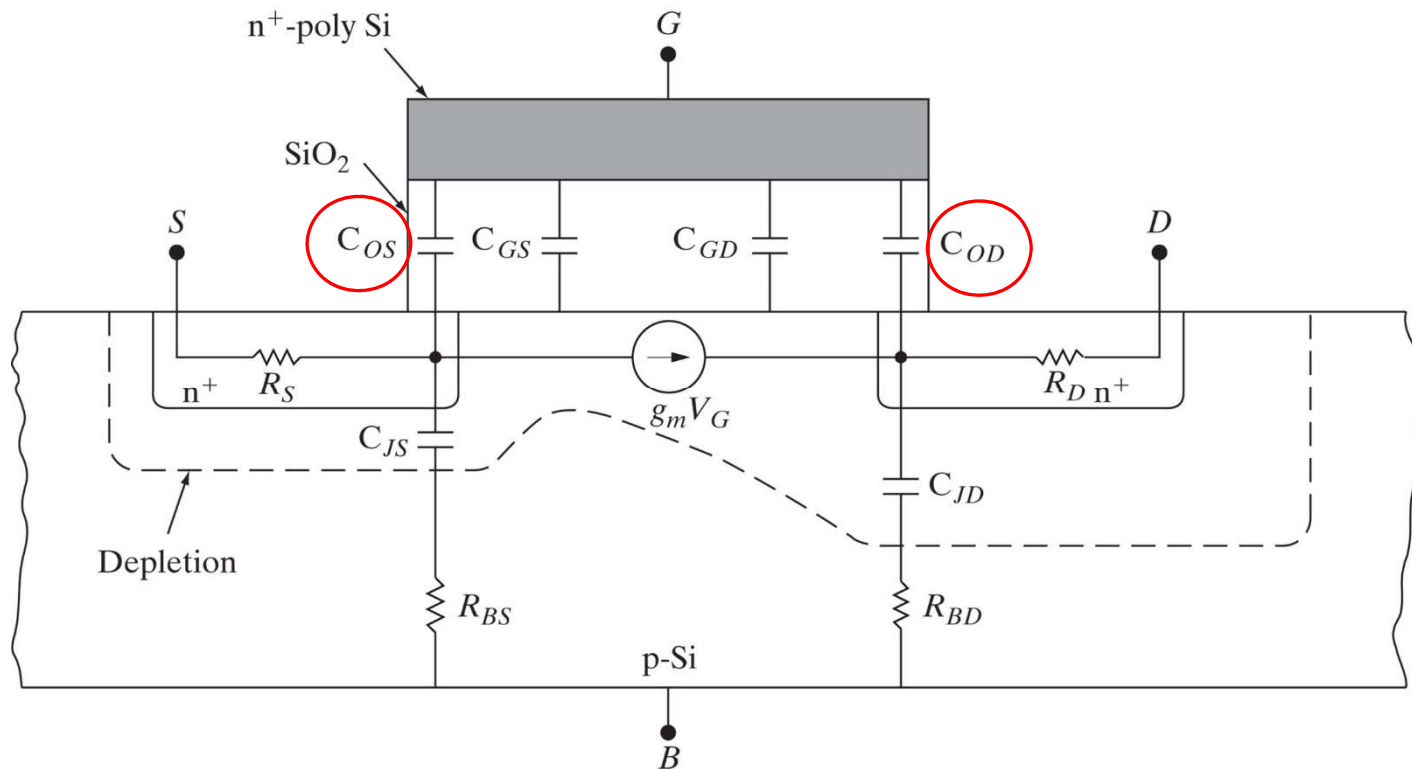
## **Chapter 9: Integrated Circuit**

**Wenjuan Zhu**

# Outline

- ⇒ • Equivalent circuit for the MOSFET
- Resistive load-NMOSFET-common-source amplifier
- CMOS inverter (Integrated Circuits)
- CMOS processing

# Equivalent circuit of a MOSFET



- **Gate capacitance:** sum of distributed capacitance from gate to channel ( $C_{GS}$ ,  $C_{GD}$ ) and overlap capacitance ( $C_{OS}$ ,  $C_{OD}$ ).  $C_{OD}$  is known as Miller overlap capacitance, represents a feedback path.
- **Gate controlled constant-current source**
- **pn junction depletion capacitance** ( $C_{JS}$ ,  $C_{JD}$ ),
- **parasitic resistance** ( $R_S$ ,  $R_D$ )

# Equivalent circuit of a MOSFET

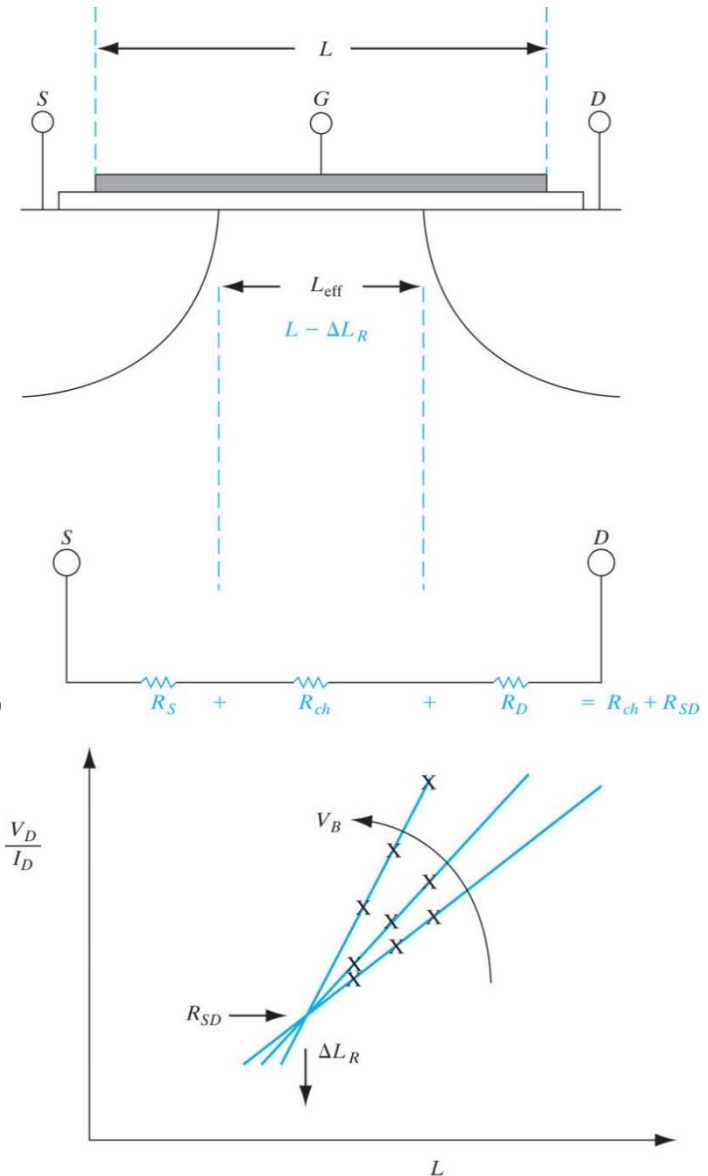
**Effective channel length:**

$$L_{eff} = L - \Delta L_R$$

$\Delta L_R$  is the spread of source  
drain under the gate

$$\frac{V_D}{I_D} = R_{Ch} + R_{SD} = \frac{L - \Delta L_R}{Z - \Delta Z} \frac{1}{\mu_n C_i (V_G - V_T)} + R_{SD}$$

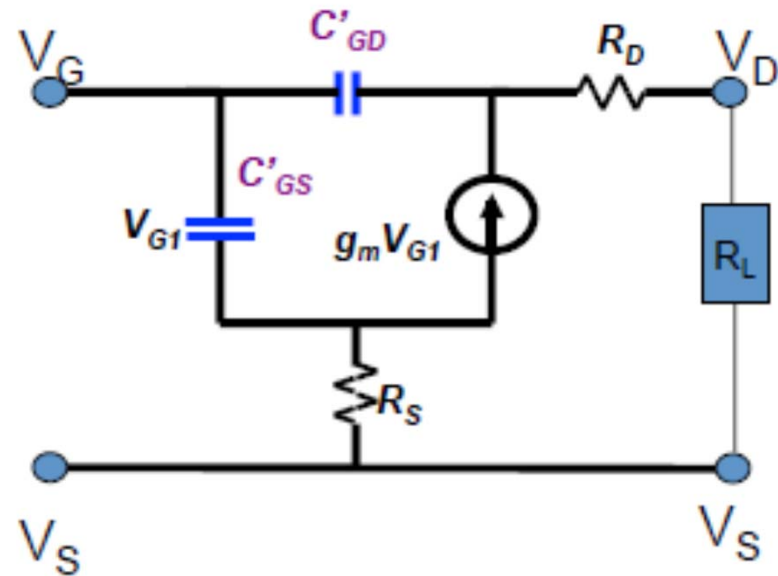
$\Delta Z$  is the width reduction due to  
isolation process



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# Equivalent circuit of MOSFET (simplified model)

- The MOSFET acts like a voltage controlled current source
- The gate-drain capacitance acts as a feedback path
- The source and drain resistance induce ohmic losses and reduce drain current for a given drain voltage



Neglecting  $R_S$  and  $R_D$ :

$$\frac{V_{out}}{V_{in}} = \frac{g_m V_G R_L}{V_G} = g_m R_L$$

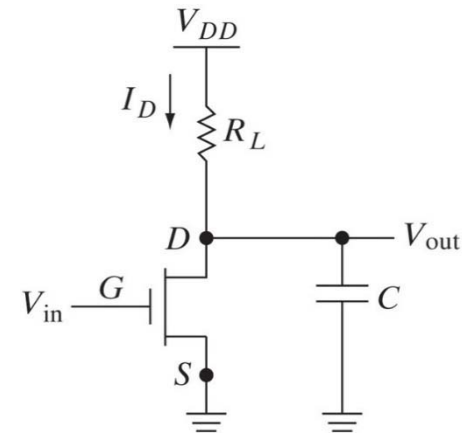
# Outline

- Equivalent circuit for the MOSFET (small signal analysis)
- ⇒ • Resistive load-NMOSFET-common-source amplifier
- CMOS inverter (Integrated Circuits)
- CMOS processing

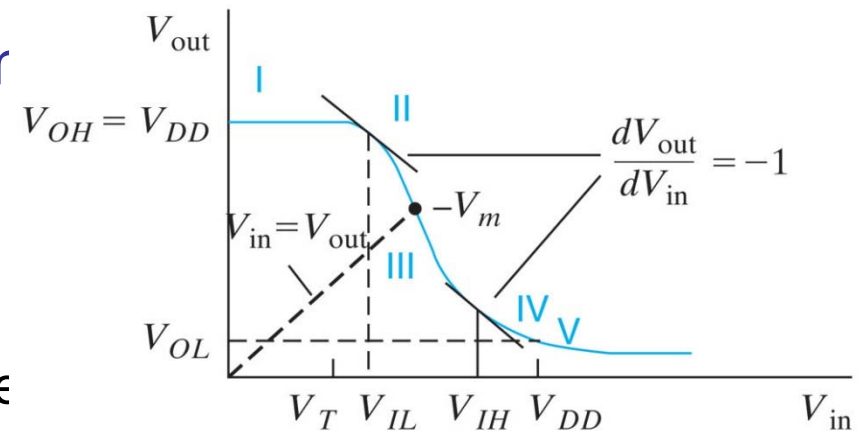
# Resistive load-NMOSFET

- Gate voltage low - no current flow, no voltage drop across  $R_L$  and  $V_{out}$  is high
- Gate voltage high -current flow, large voltage drop across  $R_L$  and  $V_{out}$  is low
- Voltage Transfer Characteristic (VTC): output voltage as a function of input bias

- $V_{OH}$ : logic high level
- $V_{OL}$ : logic low level
- $V_{IL}$  and  $V_{IH}$ : unity gain points (between  $V_{IL}$  and  $V_{IH}$  the input is amplified)
- $V_m$ : logic threshold, point where output equals input



(a) Inverter



(c) Voltage transfer characteristic

# Resistive load-NMOSFET

- Load line used to create VTC (resistor current equals FET current)

When  $V_G$  is high, MOSFET is on:

Linear region

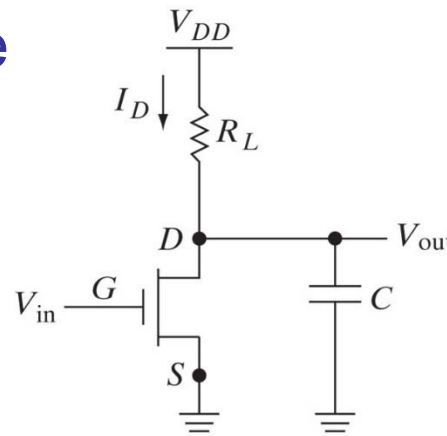
$$I_D = \frac{\mu_n Z C_i}{L} \left[ (V_G - V_T) V_D - \frac{1}{2} V_D^2 \right]$$

Saturation region:

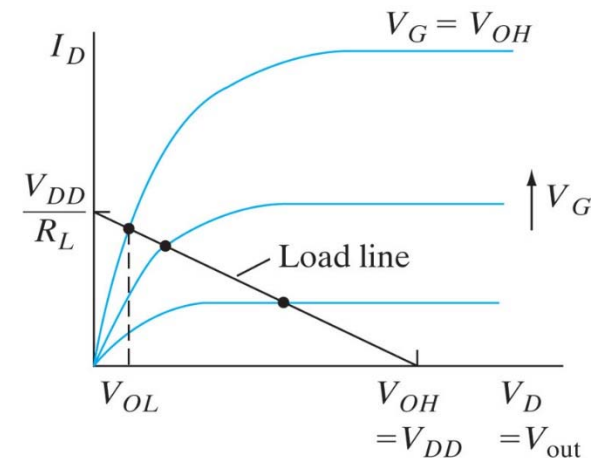
$$I_D(\text{sat.}) = \frac{Z}{2L} \mu_n C_i (V_G - V_T)^2$$

Resistor current (equal to MOSFET current):

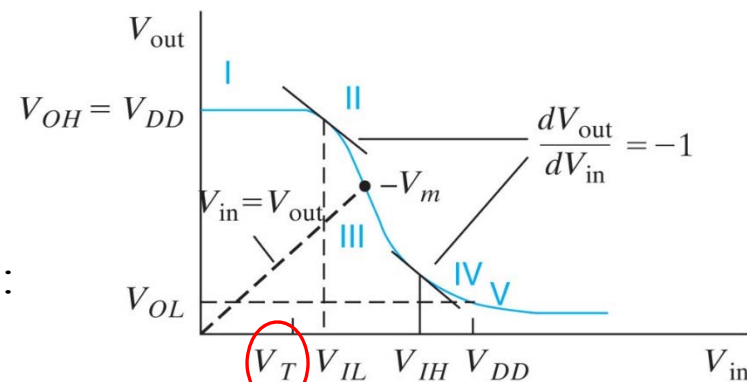
$$I_D = I_L = \frac{V_{DD} - V_{OL}}{R_L}$$



(a) Inverter



(b) Drain characteristics and load line



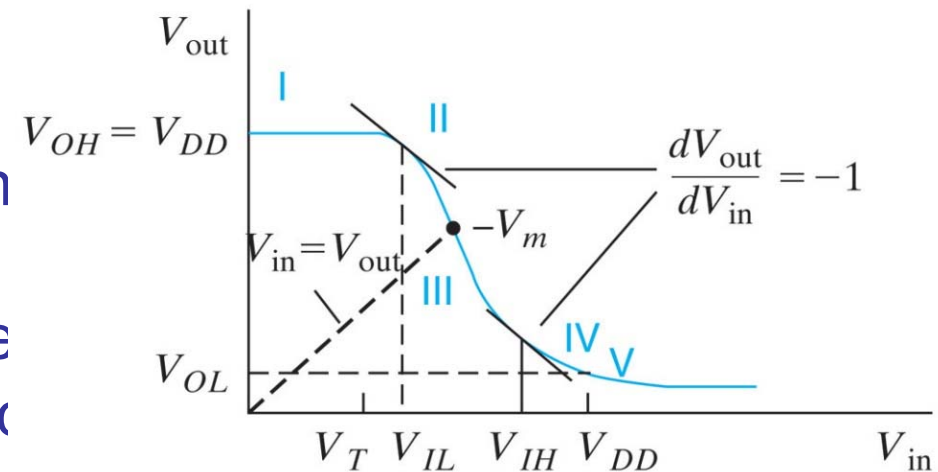
(c) Voltage transfer characteristic

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# Resistive load-NMOSFET inverter

- Ideally:
  - Region III should be as steep as possible (high gain)
  - $V_m$  should be close to  $V_{DD}/2$
- Noise immunity (noise margin how much variation in input voltage can be tolerated while still having correct output logic level)
- Problems with resistive inverter:
  - power dissipation in resistor
  - $V_{OL}$  is not zero
- Solution: CMOS

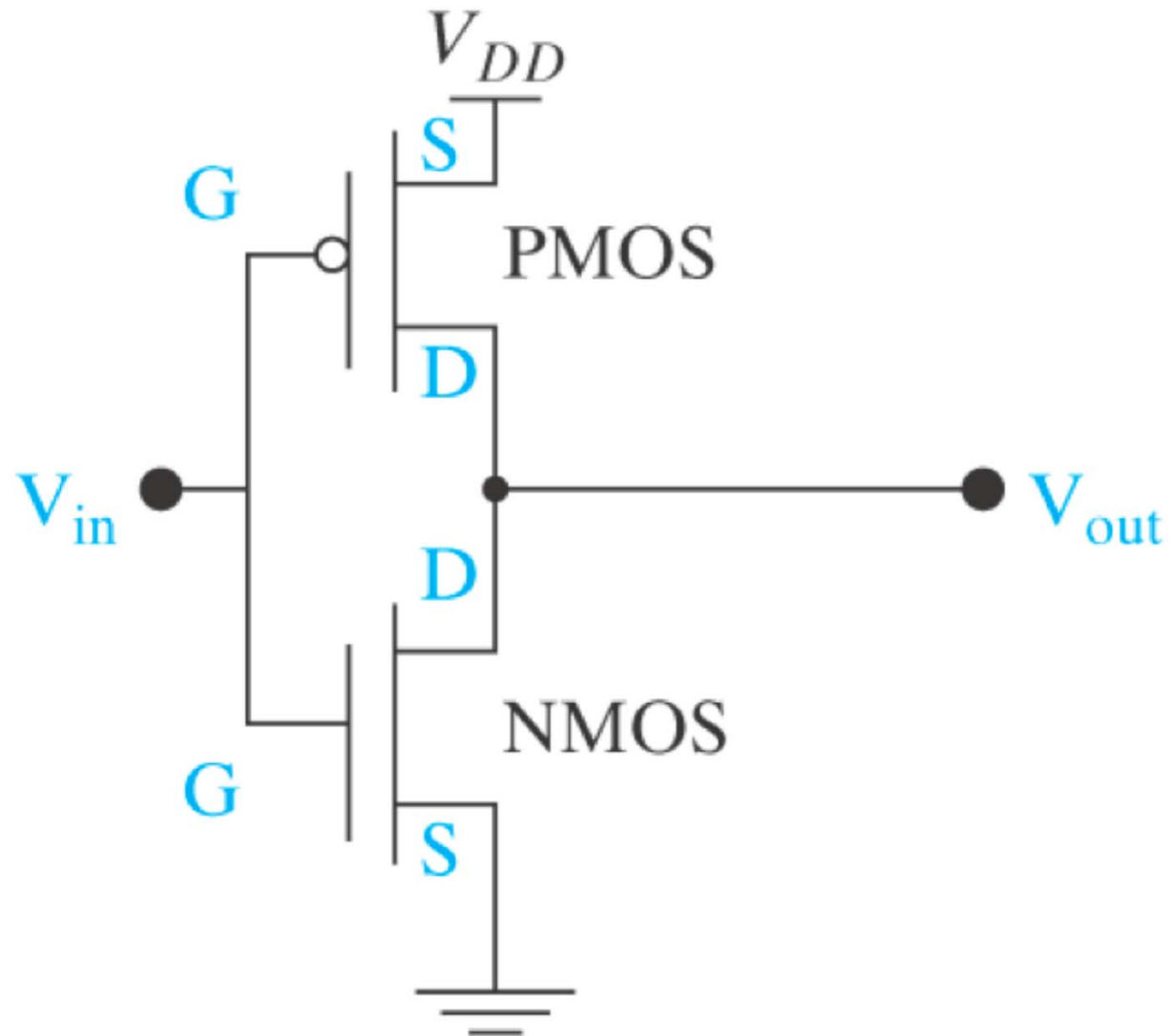


(c) Voltage transfer characteristic

# Outline

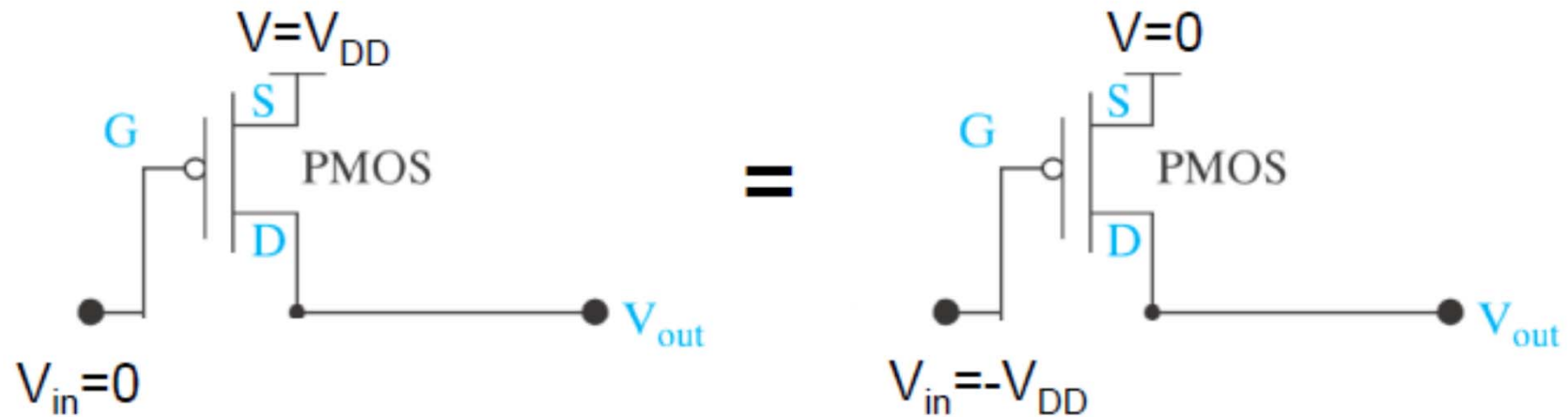
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# CMOS Inverter

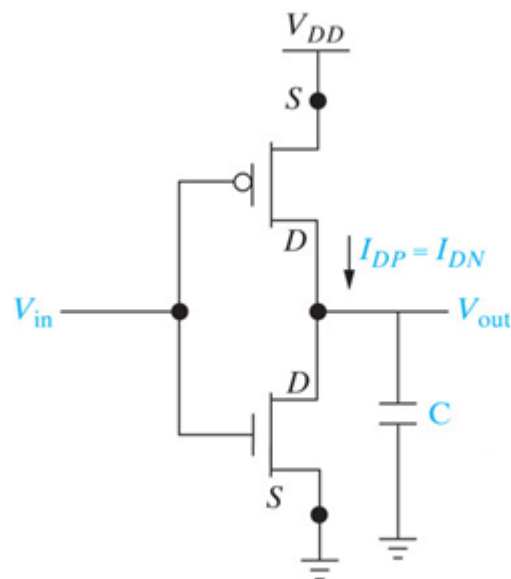


# PMOSFET bias comments

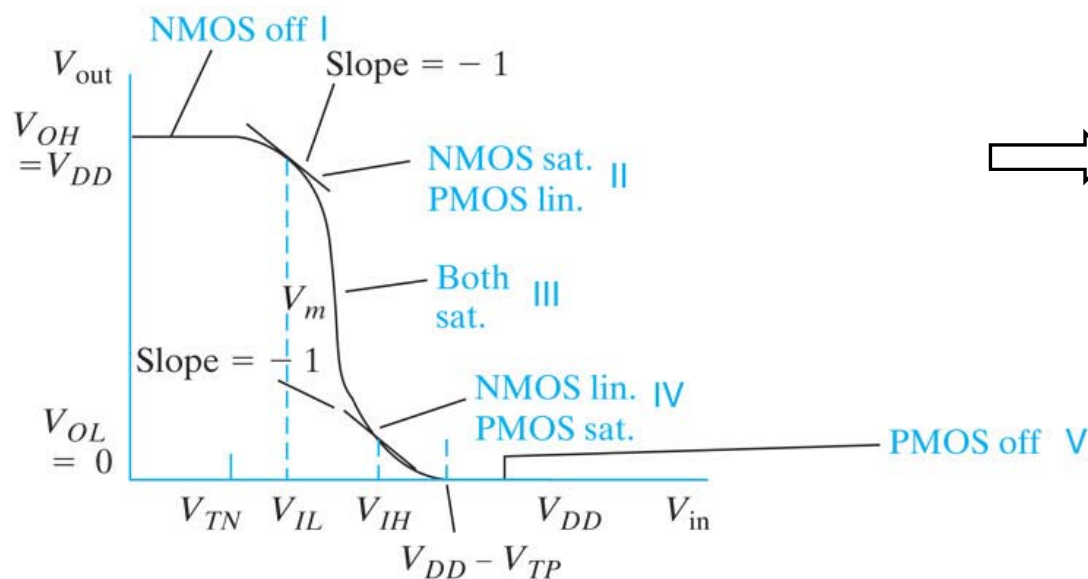
From a PMOS channel conductance perspective



# CMOS inverter voltage transfer characteristics

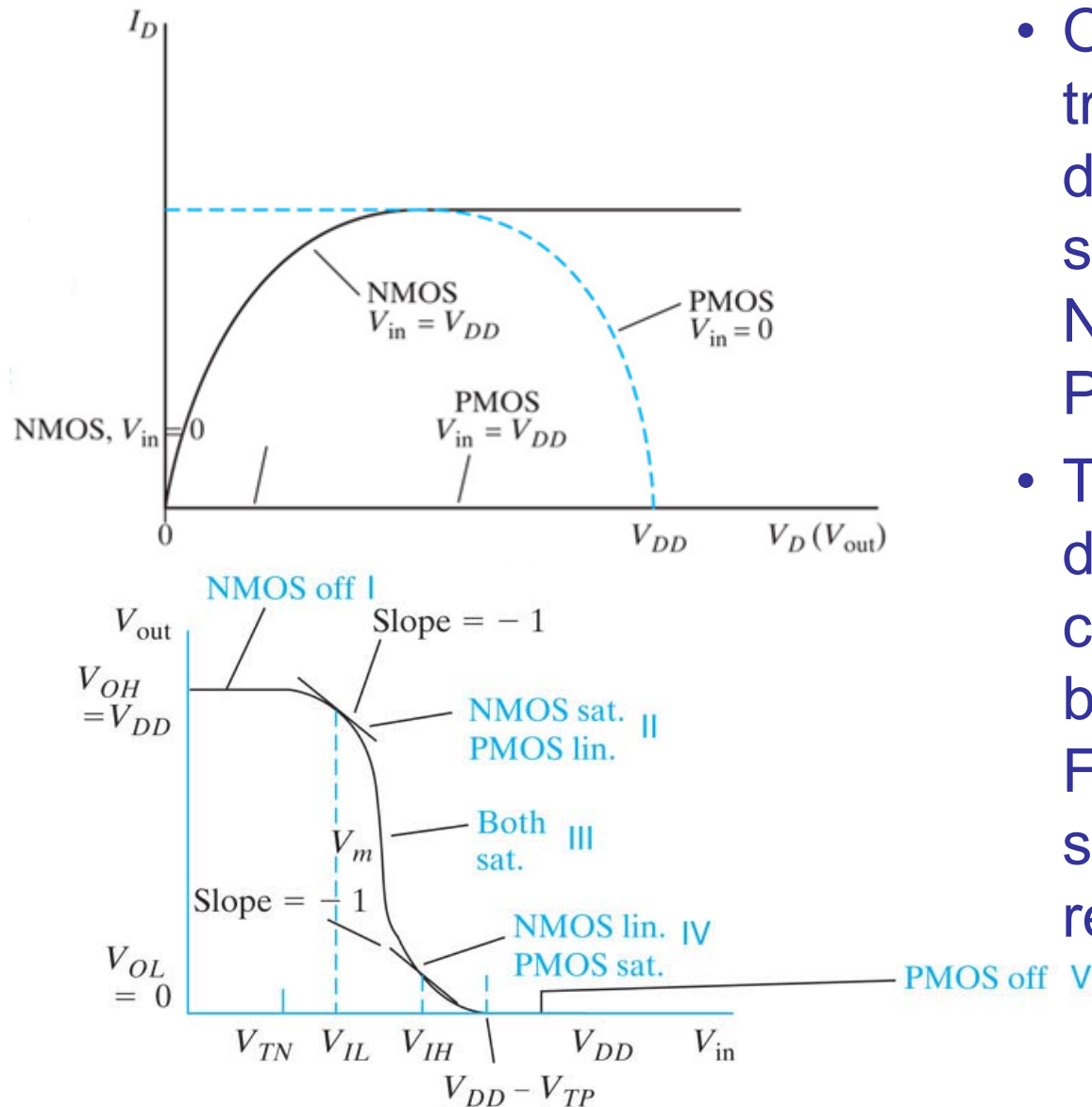


- When  $V_{in}$  is low, NMOS is off, PMOS is on  $\rightarrow V_{out}$  is high
- When  $V_{in}$  is high, NMOS is on, PMOS is off  $\rightarrow V_{out}$  is low



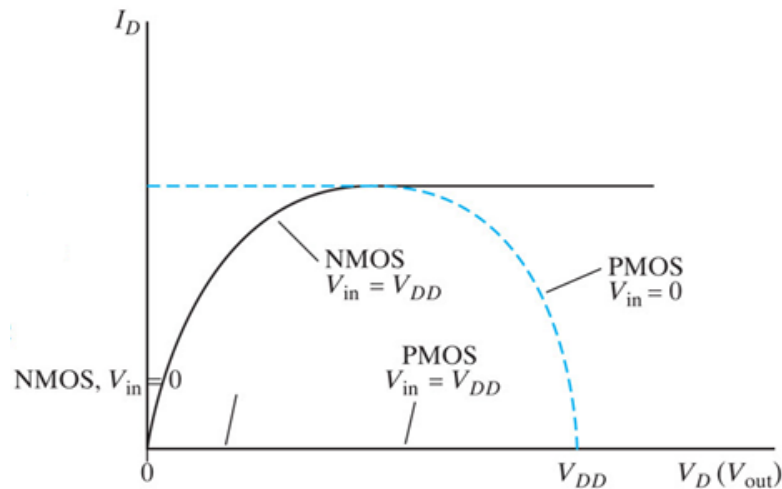
$\Rightarrow$  **Inverter**

# CMOS inverter voltage transfer characteristics



- Overall circuit voltage transfer characteristic determined by solving the set of equations where the NMOS current equal to the PMOS current
- The  $I_D$  relationship used to determine the operation characteristic is chosen based on whether the FETs are in the linear or saturation operating regions

# CMOS inverter voltage transfer characteristics



Region II Current Calculation

NMOSFET Drain Current (Saturation):

$$I_{DN} = \frac{k_n}{2} (V_{in} - V_{TN})^2$$

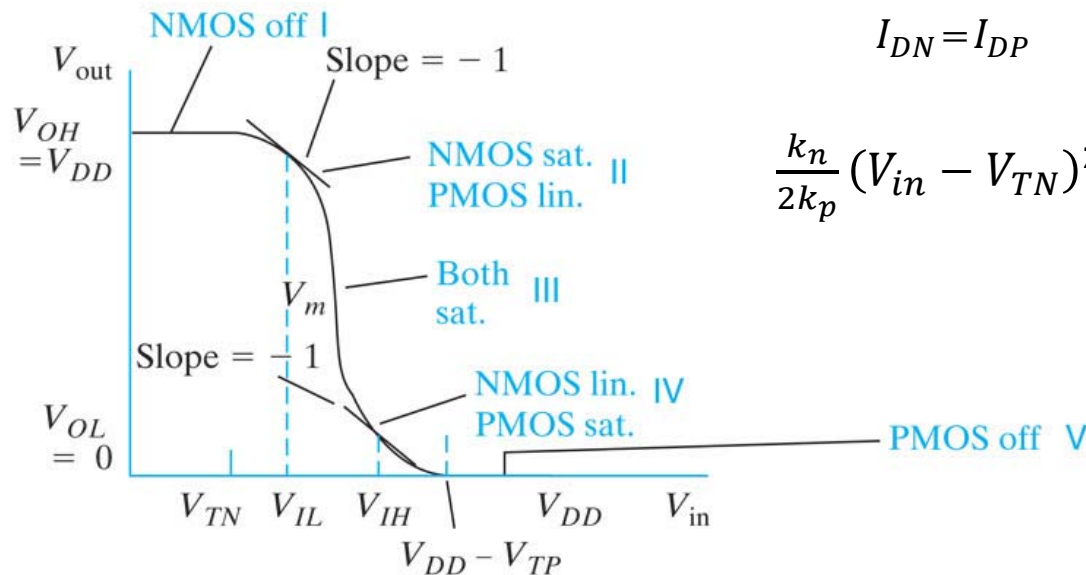
PMOSFET Drain Current (Linear):

$$I_{DP} = k_p \left[ (V_{DD} - V_{in}) + V_{TP} - \frac{(V_{DD} - V_{out})}{2} \right] (V_{DD} - V_{out})$$

To determine operation point (VTC):

$$I_{DN} = I_{DP} \quad \text{So:}$$

$$\frac{k_n}{2k_p} (V_{in} - V_{TN})^2 = \left[ \frac{V_{DD}}{2} - V_{in} + V_{TP} + \frac{V_{out}}{2} \right] (V_{DD} - V_{out})$$



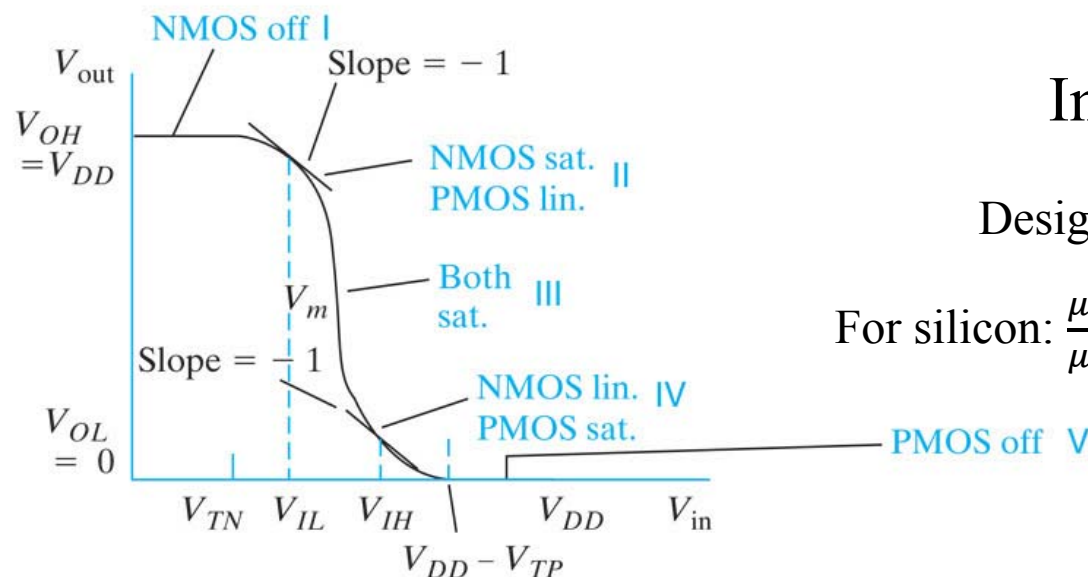
# CMOS transition voltage

- VTC transition region  $V_m$  occurs at

$$V_{in} = V_{out}$$

$$\Rightarrow V_{in} = (V_{DD} + \chi V_{TN} + V_{TP}) / (1 + \chi)$$

$$\chi = \sqrt{\frac{k_n}{k_p}} = \sqrt{\frac{\mu_n (Z/L)_n}{\mu_p (Z/L)_p}}$$



In order to have  $V_m \sim \frac{V_{DD}}{2}$

Design device such that  $V_{TN} = -V_{TP}$  and  $\chi = 1$

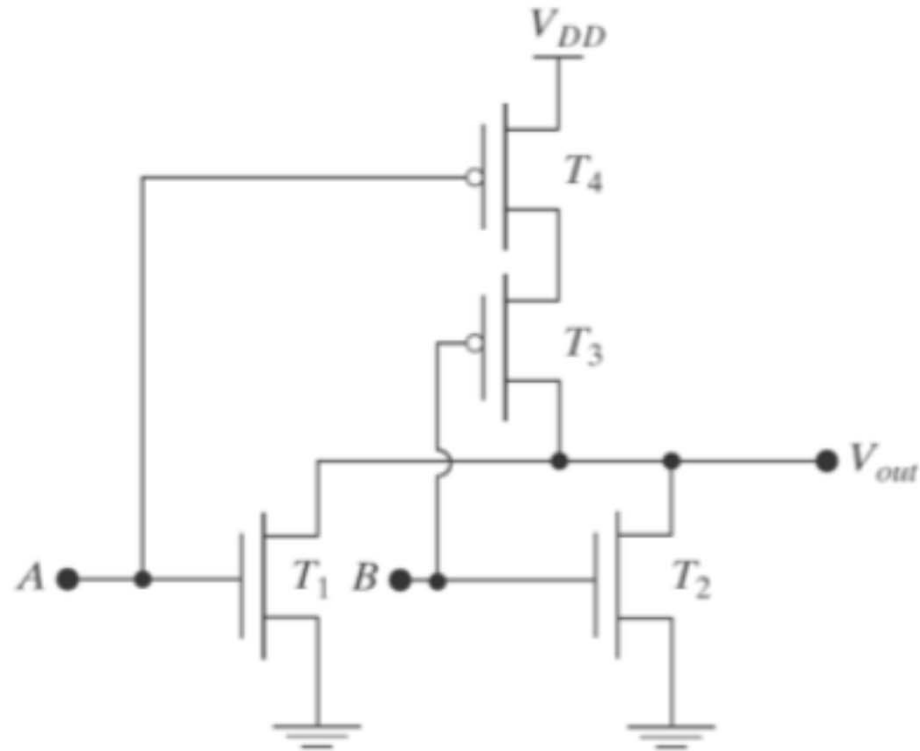
For silicon:  $\frac{\mu_n}{\mu_p} \approx 2$ , make device  $(Z/L)_p = 2(Z/L)_n$



# CMOS NOR



A	B	Out
0	0	1
0	1	0
1	0	0
1	1	0

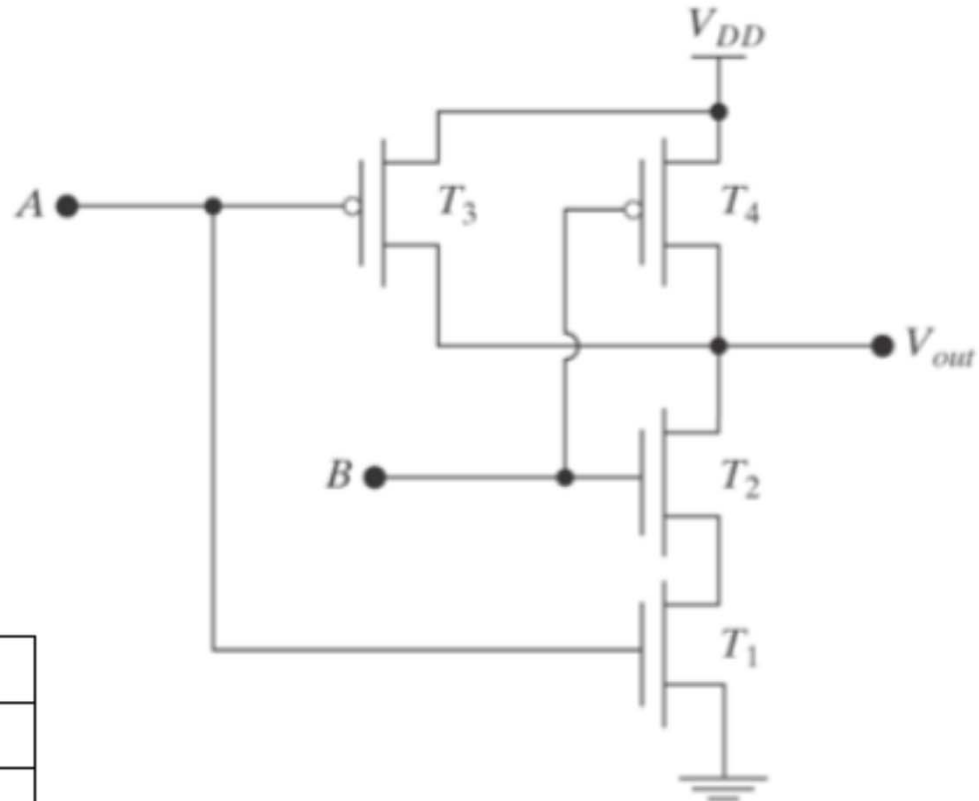


PMOS in series (slower)

# CMOS NAND



A	B	Out
0	0	1
0	1	1
1	0	1
1	1	0



NMOS in series (faster)

# Power dissipation

The input capacitance of the inverter is the parallel combination of the NMOSFET and PMOSFET:

$$C_{inv} = C_i \{ (ZL)_N + (ZL)_P \}$$

Multiplying this term by the fan-out gives a total load capacitance of "C"

The energy expended in charging "C" is given by integrating the product of the time-dependent voltage and the time-dependent current:

$$E_C = \int i_p(t) [V_{DD} - v(t)] dt = V_{DD} \int i_p(t) dt - \int i_p(t) v(t) dt$$

but  $i_p(t) = C \frac{dv(t)}{dt}$  so:

$$E_C = V_{DD} \int C \frac{dv(t)}{dt} dt - \int C v(t) \frac{dv(t)}{dt} dt = CV_{DD} \int_0^{V_{DD}} dv - C \int_0^{V_{DD}} v dv = CV_{DD}^2 - \frac{1}{2} CV_{DD}^2 = \frac{1}{2} CV_{DD}^2$$

During a discharge cycle:

$$E_d = \int i_n(t) v(t) dt = - \int_{V_{DD}}^0 C v dv = \frac{1}{2} CV_{DD}^2$$

For a charge/discharge frequency " $f$ ":

$$P = CV_{DD}^2 f$$

# Switch delay

The propagation delay time  $t_p$  is a metric for the switching speed of the gate.

$t_{PHL} \equiv$  the time for the output to transition from  $V_{OH}$  to  $V_{OH} / 2$

$t_{PLH} \equiv$  the time for the output to transition from  $V_{OL}$  to  $V_{OH} / 2$

The time needed to reach  $V_{OH} / 2$  is found by dividing charge stored in the capacitor by the charge or discharge current. Since the transistor providing the current is in

saturation, and  $I(sat) = \frac{k}{2}(V_{DD} - V_T)^2$  :

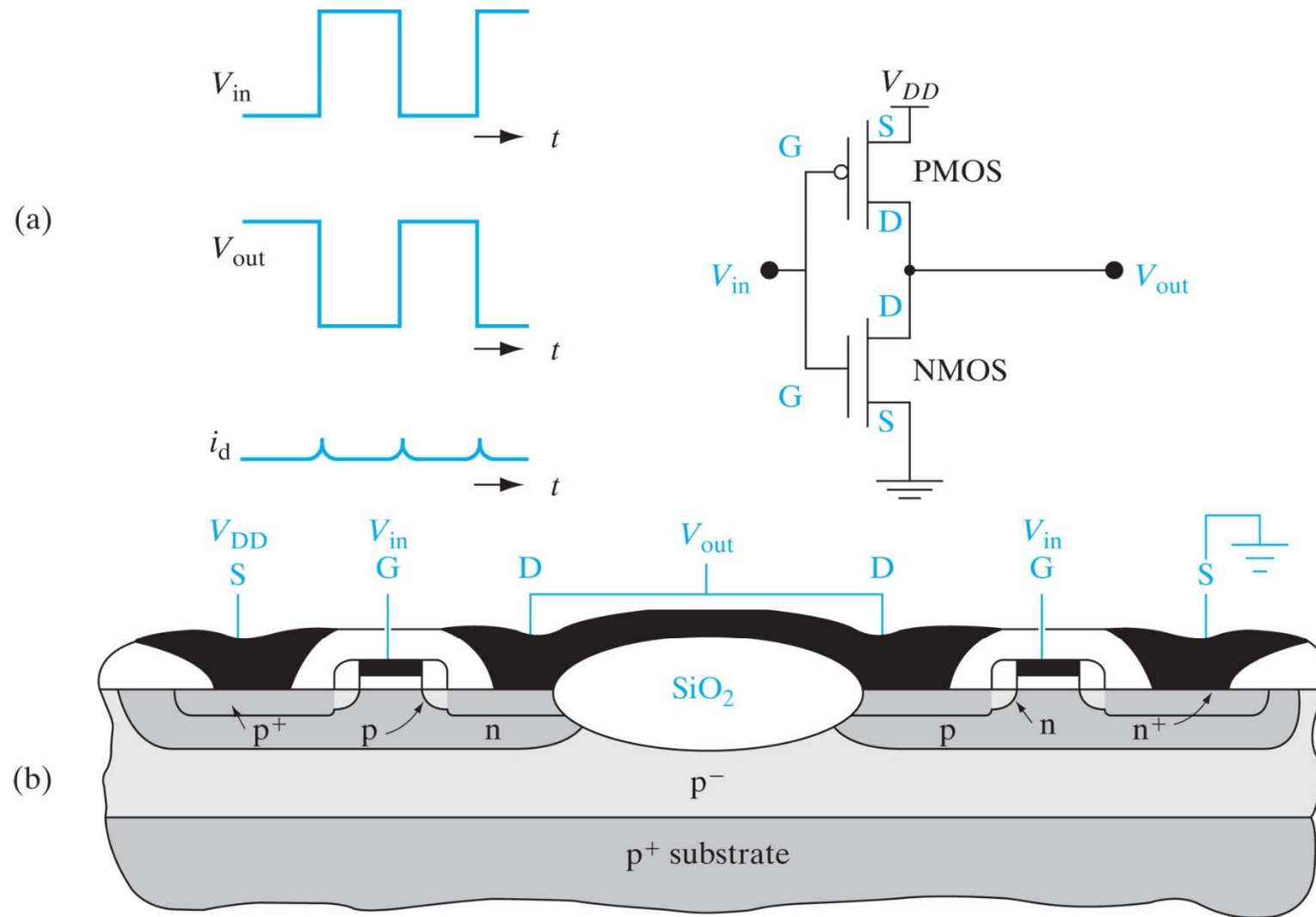
$$t_{PHL} = \frac{\frac{1}{2}CV_{DD}}{I_{DN}} = \frac{\frac{1}{2}CV_{DD}}{\frac{k_N}{2}(V_{DD} - V_{TN})^2}$$

$$t_{PLH} = \frac{\frac{1}{2}CV_{DD}}{I_{DP}} = \frac{\frac{1}{2}CV_{DD}}{\frac{k_P}{2}(V_{DD} + V_{TP})^2}$$

# Outline

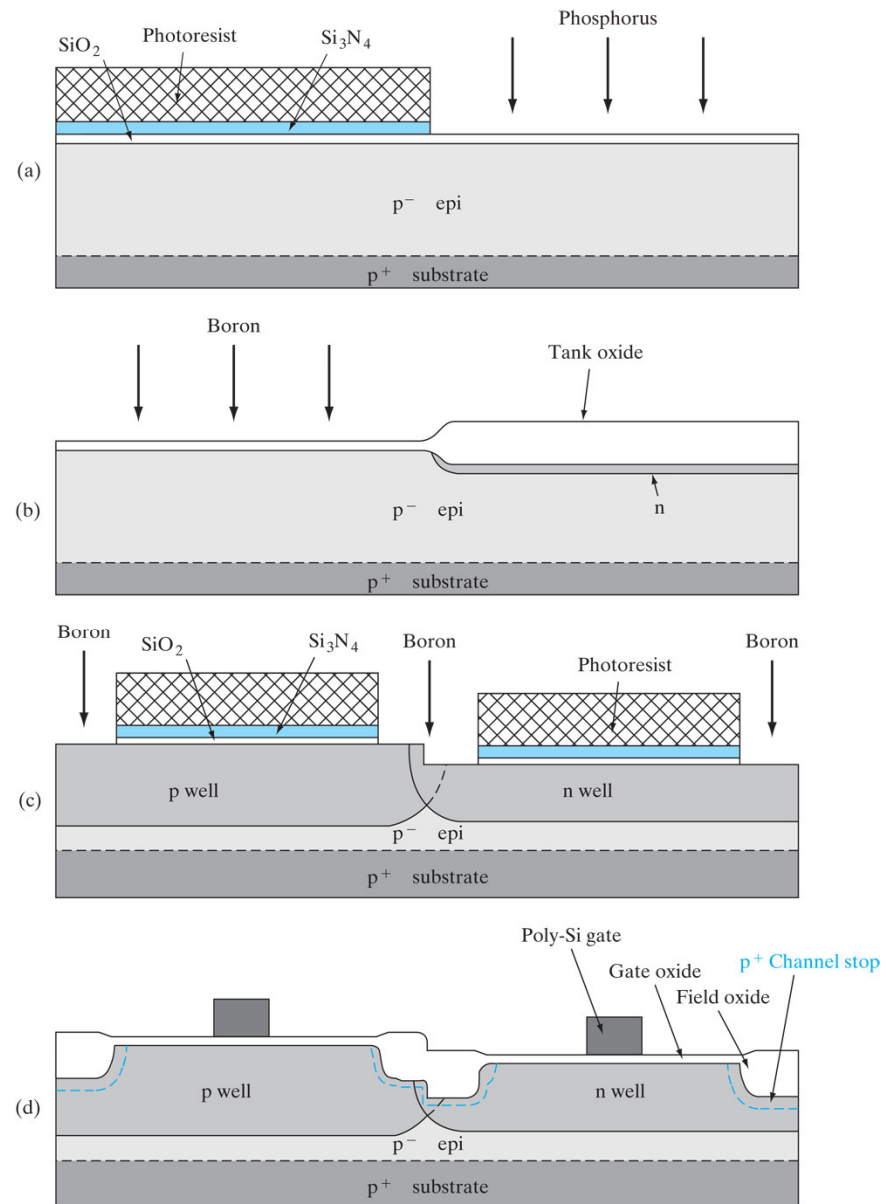
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# CMOS processing



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# Self aligned process



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# NMOS fabrication in p-well

